Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/064,455	HAN, CHIA-HUI	
Examiner	**Art Unit**	
Sean Reilly	2153	

SEARCHED			
Class	Subclass	Date	Examiner
709	249-250	4/26/2007	SR
719	321, 327	4/27/2007	SR

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
709	250	8/8/07	SR
719	321	8/8/07	SR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor and Assignee double patenting search.	4/26/2007	SR
NPL search - IEEE database.	4/26/2007	SR
Consulted w/ Primary Examiner Beatriz Prieto 2142; search strategy	4/26/2007	SR
Consulted w/ Primary Examiner Van Nguyen Class 719, AU 2194; allwable subject matter	4/27/2007	SR
Updated class search	8/8/07	SR